IXYS

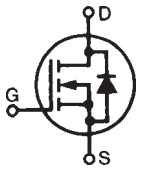
Advance Technical Information

Trench Gate Power MOSFET

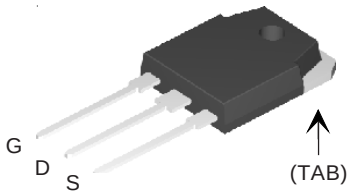
IXTQ 180N055T
IXTA 180N055T
IXTP 180N055T

V_{DSS} = 55 V
I_{D25} = 180 A
$R_{DS(on)}$ = 4.0 mΩ

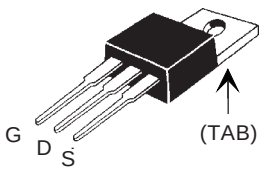
N-Channel Enhancement Mode



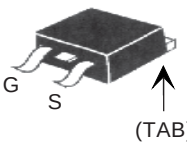
TO-3P (IXTQ)



TO-220 (IXTP)



TO-263 (IXTA)



G = Gate D = Drain
S = Source TAB = Drain

Symbol	Test Conditions	Maximum Ratings	
V_{DSS}	T_J = 25°C to 175°C	55	V
V_{DGR}	T_J = 25°C to 175°C; R_{GS} = 1 MΩ	55	V
V_{GSM}		±20	V
I_{D25}	T_C = 25°C	180	A
I_{DRMS}	External lead current limit	75	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	600	A
I_{AR}	T_C = 25°C	75	A
E_{AS}	T_C = 25°C	1.0	J
dv/dt	$I_S \le I_{DM}$, di/dt ≤ 100 A/µs, $V_{DD} \le V_{DSS}$, $T_J \le 150°C$, R_G = 10 Ω	3	V/ns
P_D	T_C = 25°C	360	W
T_J		-55 ... +175	°C
T_{JM}		175	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C
	Maximum tab temperature for soldering TO-263 package for 10s	260	°C
M_d	Mounting torque (TO-3P / TO-220)	1.13/10	Nm/lb.in.
Weight	TO-3P	5.5	g
	TO-220	4	g
	TO-263	3	g

Symbol (T_J = 25°C, unless otherwise specified)	Test Conditions	Characteristic Values Min.	Typ.	Max.	
V_{DSS}	V_{GS} = 0 V, I_D = 250 µA	55			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 1 mA	2.0		4.0	V
I_{GSS}	V_{GS} = ±20 V_{DC}, V_{DS} = 0			±200	nA
I_{DSS}	$V_{DS} = V_{DSS}$			1	µA
	V_{GS} = 0 V, T_J = 125°C			250	µA
$R_{DS(on)}$	V_{GS} = 10 V, I_D = 50 A, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %		3.3	4.0	mΩ

Features

- International standard packages
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect

Advantages

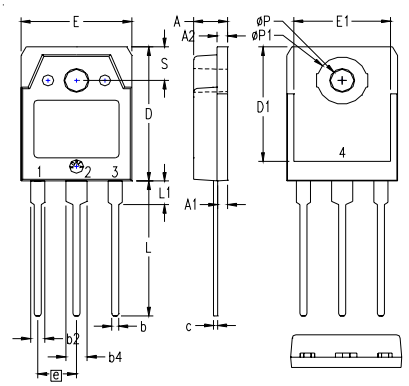
- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) Min.	Typ.	Max.	
g_{fs}	V_{DS}= 10 V; I_D = 50A, pulse test	70	90		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		5800		pF
C_{oss}			1190		pF
C_{rss}			138		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 40 V, I_D = 40A R_G = 5 Ω (External)		37		ns
t_r			61		ns
$t_{d(off)}$			65		ns
t_f			36		ns
$Q_{g(on)}$	V_{GS}= 10 V, V_{DS} = 30 V, I_D = 90 A		160		nC
Q_{gs}			46		nC
Q_{gd}			47		nC
R_{thJC}				0.42	K/W
R_{thCK}	(TO-3P) (TO-220)		0.21 0.25		K/W K/W

Source-Drain Diode

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) Min.	typ.	Max.	
I_S	V_{GS} = 0 V			180	A
I_{SM}	Repetitive			600	A
V_{SD}	I_F = 50 A, V_{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %			1.2	V
t_{rr}	I_F = 25 A -di/dt = 100 A/µs		80		ns
Q_{RM}	V_R = 25 V		0.4		µC

TO-3P (IXTQ) Outline

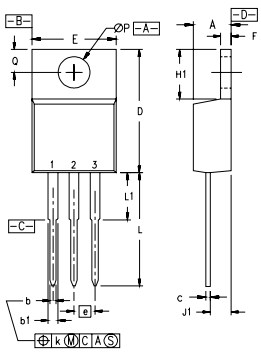


1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – DRAIN (COLLECTOR)

SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	.185	.193	4.70	4.90
A1	.051	.059	1.30	1.50
A2	.057	.065	1.45	1.65
b	.035	.045	0.90	1.15
b2	.075	.087	1.90	2.20
b4	.114	.126	2.90	3.20
c	.022	.031	0.55	0.80
D	.780	.791	19.80	20.10
D1	.665	.677	16.90	17.20
E	.610	.622	15.50	15.80
E1	.531	.539	13.50	13.70
e	.215 BSC		5.45 BSC	
L	.779	.795	19.80	20.20
L1	.134	.142	3.40	3.60
øP	.126	.134	3.20	3.40
øP1	.272	.280	6.90	7.10
S	.193	.201	4.90	5.10

All metal area are tin plated.

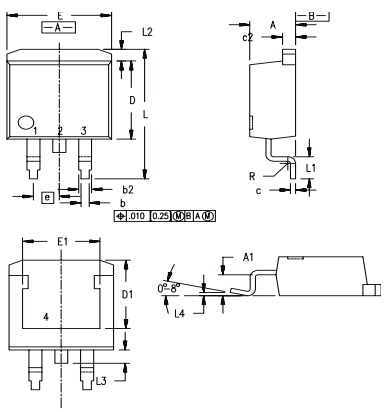
TO-220 (IXTP) Outline



Pins: 1 - Gate 2 - Drain

SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	.170	.190	4.32	4.83
b	.025	.040	0.64	1.02
b1	.045	.065	1.15	1.65
c	.014	.022	0.35	0.56
D	.580	.630	14.73	16.00
E	.390	.420	9.91	10.66
e	.100 BSC		2.54 BSC	
F	.045	.055	1.14	1.40
H1	.230	.270	5.85	6.85
J1	.090	.110	2.29	2.79
k	0	.015	0	0.38
L	.500	.550	12.70	13.97
L1	.110	.230	2.79	5.84
ØP	.139	.161	3.53	4.08
Q	.100	.125	2.54	3.18

TO-263 (IXTA) Outline



Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	4.06	4.83	.160	.190
A1	2.03	2.79	.080	.110
b	0.51	0.99	.020	.039
b2	1.14	1.40	.045	.055
c	0.46	0.74	.018	.029
c2	1.14	1.40	.045	.055
D	8.64	9.65	.340	.380
D1	7.11	8.13	.280	.320
E	9.65	10.29	.380	.405
E1	6.86	8.13	.270	.320
e	2.54	BSC	.100	BSC
L	14.61	15.88	.575	.625
L1	2.29	2.79	.090	.110
L2	1.02	1.40	.040	.055
L3	1.27	1.78	.050	.070
L4	0	0.38	0	.015
R	0.46	0.74	.018	.029

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,850,072 4,881,106 4,931,844 5,017,508 5,034,796 5,049,961 5,063,307 5,187,117 5,237,481 5,381,025 5,486,715 6,162,665 6,259,123 B1 6,306,728 B1 6,404,065 B1 6,534,343 6,583,505 6,683,344 6,710,405 B2 6,710,463 6,727,585 6,759,692

Fig. 1. Output Characteristics @ 25ºC

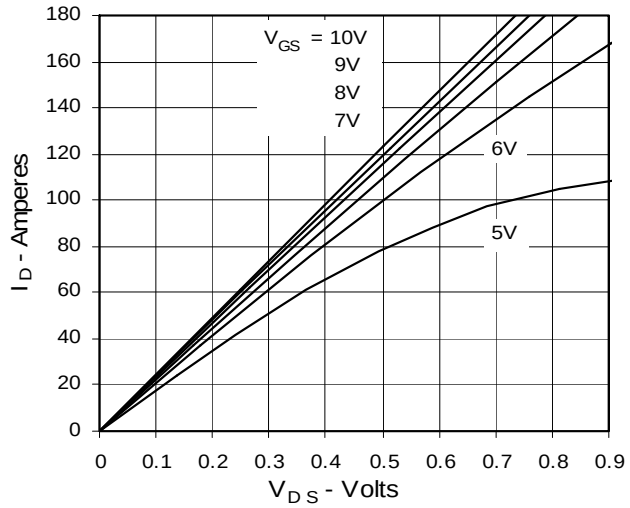


Fig. 2. Extended Output Characteristics @ 25ºC

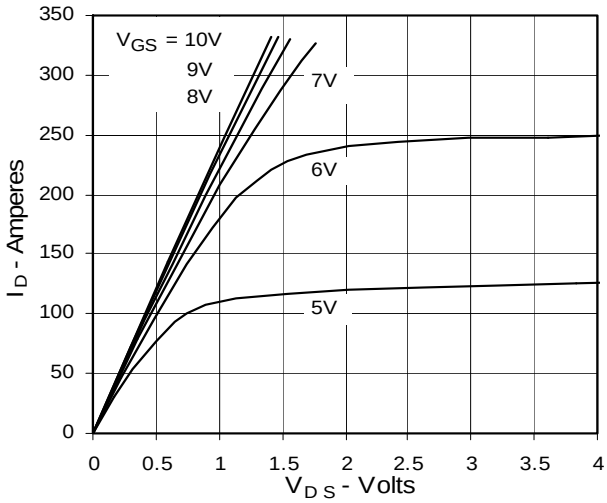


Fig. 3. Output Characteristics @ 150ºC

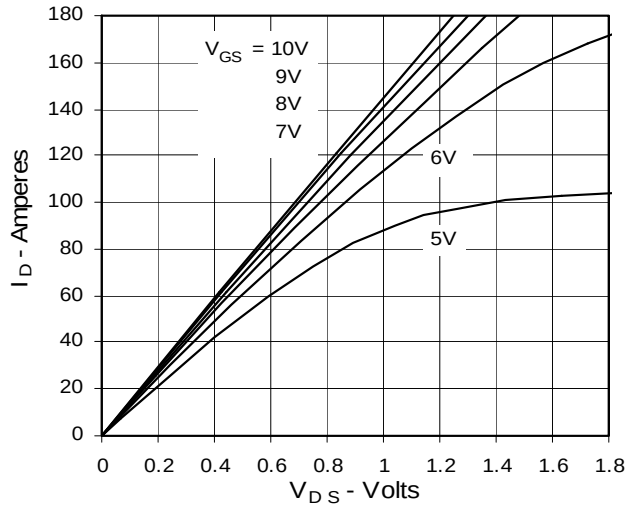


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature

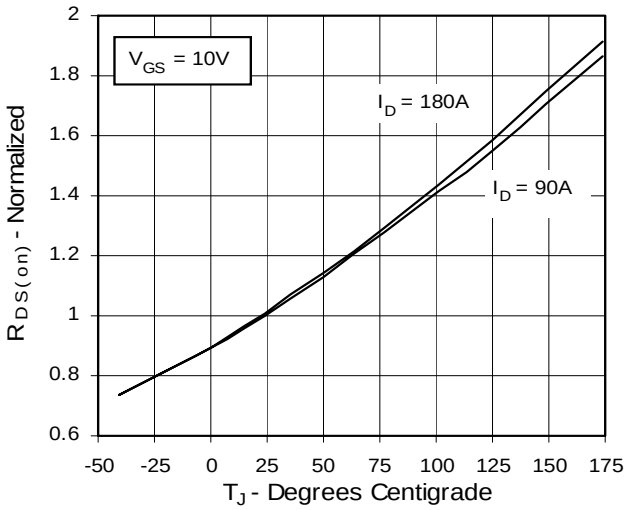


Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Drain Current

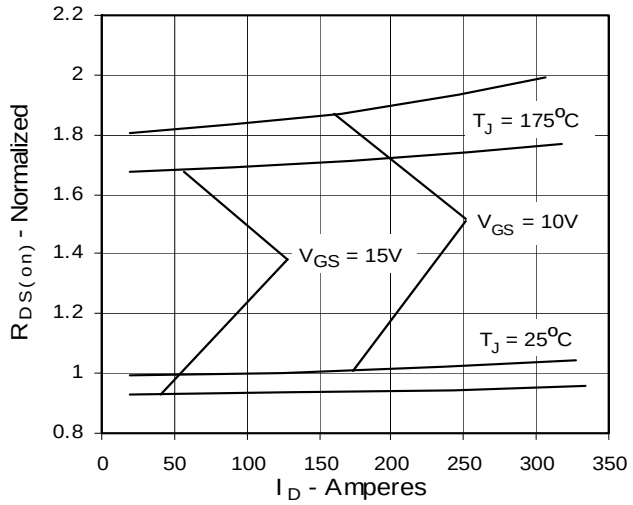


Fig. 6. Drain Current vs. Case Temperature

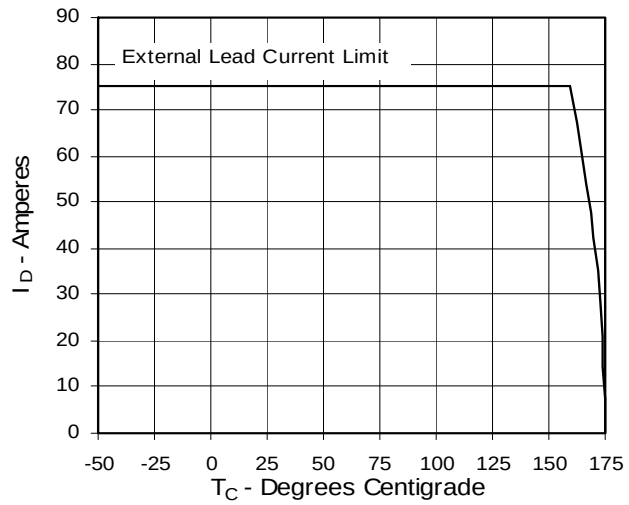


Fig. 7. Input Admittance

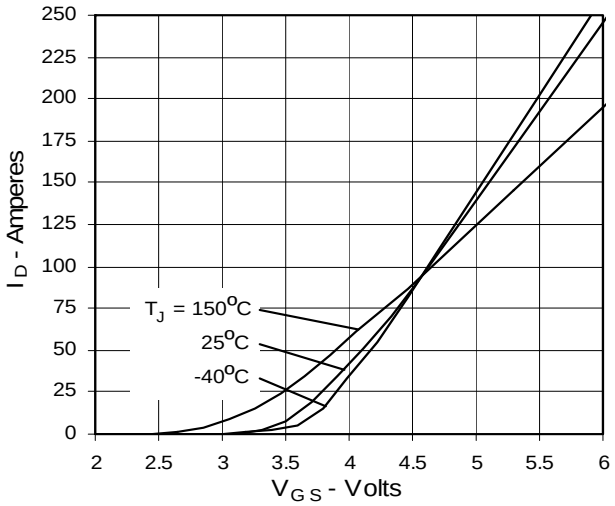


Fig. 8. Transconductance

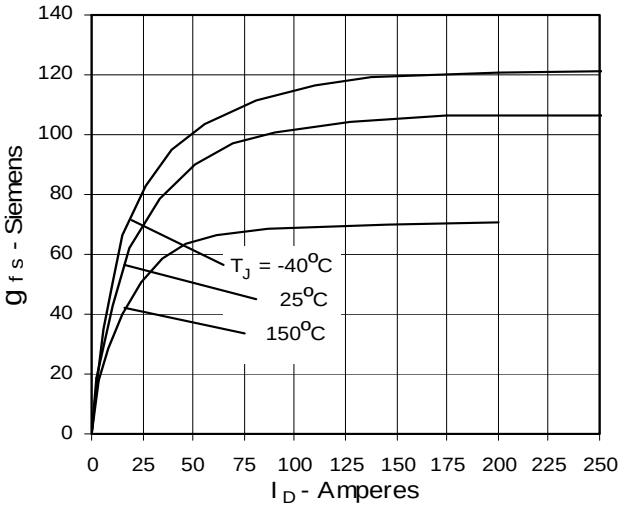


Fig. 9. Source Current vs. Source-To-Drain Voltage

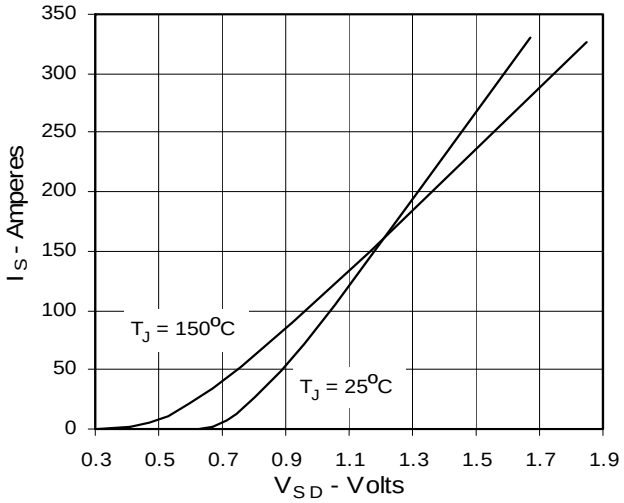


Fig. 10. Gate Charge

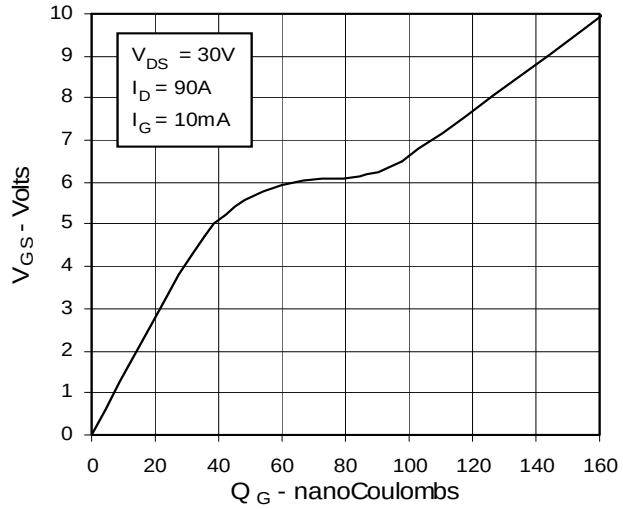


Fig. 11. Capacitance

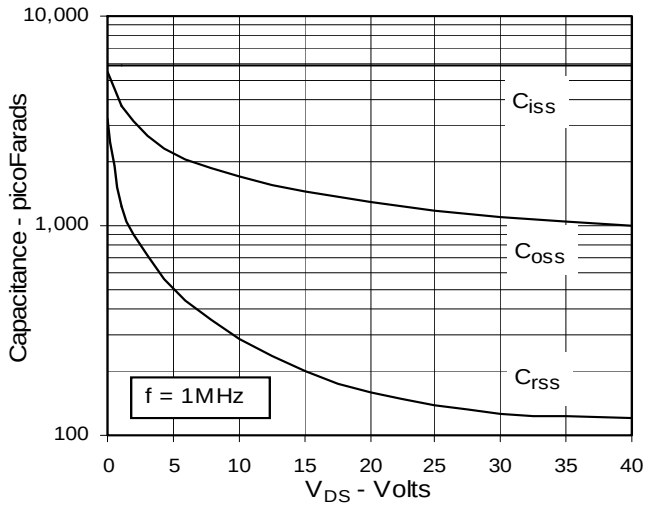


Fig. 12. Forward-Bias Safe Operating Area

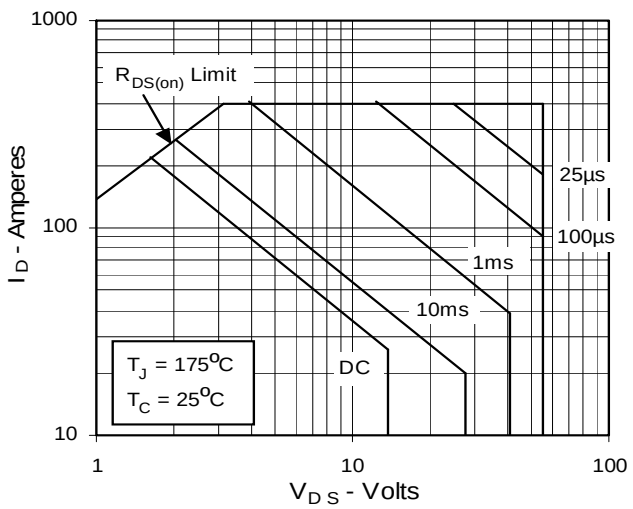


Fig. 13. Maximum Transient Thermal Resistance